











CSD87381P

SLPS405F-MARCH 2013-REVISED MARCH 2015

CSD87381P Synchronous Buck NexFET™ Power Block II

Features

- Half-Bridge Power Block
- 90% System Efficiency at 10 A
- Up to 15 A Operation
- High Density − 3 × 2.5 mm LGA Footprint
- **Double Side Cooling Capability**
- Ultra-Low Profile 0.48 mm Max
- Optimized for 5 V Gate Drive
- Low Switching Losses
- Low Inductance Package
- **RoHS** Compliant
- Halogen Free
- Pb Free

Applications

- Synchronous Buck Converters
 - High Current, Low Duty Cycle Applications
- Multiphase Synchronous Buck Converters
- POL DC-DC Converters

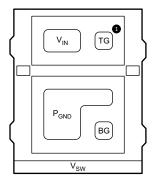
3 Description

The CSD87381P NexFET™ power block II is a highly optimized design for synchronous buck applications offering high current and high efficiency capability in a small 3 mm × 2.5 mm outline. Optimized for 5 V gate drive applications, this product offers an efficient and flexible solution capable of providing a high density power supply when paired with any 5 V gate driver from an external controller/driver.

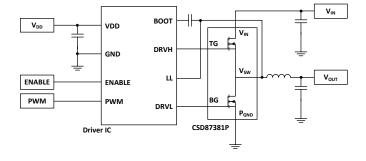
Device Information⁽¹⁾

Device	Media	Qty	Package	Ship
CSD87381P	13-Inch Reel	2500	3 × 2.5 LGA	Tape and
CSD87381PT	7-Inch Reel	250	3 × 2.5 LGA	Reel

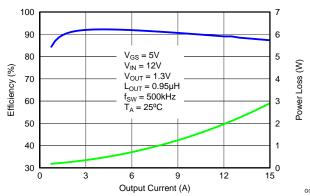
(1) For all available packages, see the orderable addendum at the end of the data sheet.



Typical Circuit



Typical Power Block Efficiency and Power Loss





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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

CI	hanges from Revision E (June 2014) to Revision F	Page
	Changed capacitance units to read pF in Figure 15	8
<u>.</u>	Changed capacitance units to read pF in Figure 16	
CI	hanges from Revision D (May 2014) to Revision E	Page
<u>.</u>	Changed "Pb Free terminal plating" feature to state "Pb Free"	1
CI	hanges from Revision C (January 2014) to Revision D	Page
•	Updated data sheet to reflect new standards	1
<u>.</u>	Corrected device dimensions	1
CI	hanges from Revision B (May 2013) to Revision C	Page
•	Updated title	1
•	Added small reel info	1
•	Added unit to test condition in Electrical Characteristics	4
<u>.</u>	Added a link for Figure 29 in Electrical Performance	14
CI	hanges from Revision A (March 2013) to Revision B	Page
	Changed R _{BJC-PCB} To: R _{BJC} in the Thermal Information table	4
<u>.</u>	Changed Figure 15	
CI	hanges from Original (March 2013) to Revision A	Page
•	Changes to a Product Preview device	1



5 Specifications

5.1 Absolute Maximum Ratings

 $T_A = 25$ °C (unless otherwise noted) (1)

			MIN	MAX	UNIT
		V _{IN} to P _{GND}	-0.8	30	
		V _{SW} to P _{GND}		30	
Voltag	je	V _{SW} to P _{GND} (10 ns)		32	V
	T_G to V_{SW}	-8	10		
		B _G to P _{GND}	-8	10	
I_{DM}	Pulsed Current Rating (2)			40	Α
P_{D}	Power Dissipation (3)			4	W
_	Avolonoho Energy	Sync FET, $I_D = 27$, $L = 0.1$ mH		36	m l
E _{AS} Avalanche Energy		Control FET, $I_D = 20$, $L = 0.1$ mH		20	mJ
T_{J}	Operating Junction		– 55	150	°C
T _{stg}	Storage Temperature Range		– 55	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

5.2 Recommended Operating Conditions

 $T_A = 25^{\circ}$ (unless otherwise noted)

			MIN	MAX	UNIT
V_{GS}	Gate Drive Voltage		4.5	8	٧
V_{IN}	Input Supply Voltage			24	٧
$f_{\sf SW}$	Switching Frequency	$C_{BST} = 0.1 \mu F \text{ (min)}$	200	1500	kHz
		No Airflow		15	
Opera	ting Current	With Airflow (200 LFM)		20	Α
		With Airflow + Heat Sink		25	
T_{J}	Operating Temperature			125	°C

5.3 Power Block Performance

 $T_A = 25^{\circ}$ (unless otherwise noted)

	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNIT
P _{LOSS}	Power Loss ⁽¹⁾	$V_{IN} = 12 \text{ V}, V_{GS} = 5 \text{ V},$ $V_{OUT} = 1.3 \text{ V}, I_{OUT} = 8 \text{ A},$ $f_{SW} = 500 \text{ kHz},$ $L_{OUT} = 0.3 \mu\text{H}, T_{J} = 25^{\circ}\text{C}$		1		W
I _{QVIN}	V _{IN} Quiescent Current	T_G to $T_{GR} = 0$ V B_G to $P_{GND} = 0$ V		10		μΑ

⁽¹⁾ Measurement made with six 10 μ F (TDK C3216X5R1C106KT or equivalent) ceramic capacitors placed across V_{IN} to P_{GND} pins and using a high current 5 V driver IC.

⁽²⁾ Pulse Duration ≤50 μs, duty cycle ≤0.01

⁽³⁾ Device mounted on FR4 material with 1 inch² (6.45 cm²) Cu



5.4 Thermal Information

 $T_A = 25$ °C (unless otherwise stated)

	THERMAL METRIC	MIN	TYP	MAX	UNIT
В	Junction-to-ambient thermal resistance (min Cu) (1)			184	
$R_{\theta JA}$	Junction-to-ambient thermal resistance (max Cu) (2)(1)			84	°C/W
Junction-to-case thermal resistance (top of package) (1)			4.9	-C/VV	
$R_{\theta JC}$	Junction-to-case thermal resistance (P _{GND} pin) ⁽¹⁾			1.65	

⁽¹⁾ R_{\text{\tinte\text{\tinte\text{\tinit}}}\text{\texitile}}}\text{\texit{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\text{\t}

5.5 Electrical Characteristics

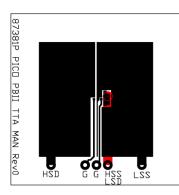
 $T_A = 25^{\circ}C$ (unless otherwise stated)

	PARAMETER	TEST CONDITIONS	Q1	Q1 Control FET			Sync FE	T	UNIT
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNII
STATIC C	HARACTERISTICS								
BV _{DSS}	Drain-to-Source Voltage	V _{GS} = 0 V, I _{DS} = 250 µA	30			30			V
I _{DSS}	Drain-to-Source Leakage Current	V _{GS} = 0 V, V _{DS} = 24			1			1	μΑ
I _{GSS}	Gate-to-Source Leakage Current	V _{DS} = 0 V, V _{GS} = 10			100			100	nA
V _{GS(th)}	Gate-to-Source Threshold Voltage	V _{DS} = V _{GS} , I _{DS} = 250 µA	1.1		1.9	1		1.7	V
	B :	$V_{GS} = 4.5 \text{ V}, I_{DS} = 8 \text{ A}$		15.7	18.9		7	8.4	_
R _{DS(on)}	Drain-to-Source On-Resistance	V _{GS} = 8 V, I _{DS} = 8 A		13.6	16.3		6.3	7.6	mΩ
g _{fs}	Transconductance	V _{DS} = 10 V, I _{DS} = 8 A		40			89		S
DYNAMIC	CHARACTERISTICS								
C _{ISS}	Input Capacitance (1)	V _{GS} = 0 V, V _{DS} = 15		434	564		1020	1320	pF
Coss	Output Capacitance (1)	V,		225	293		308	400	pF
C _{RSS}	Reverse Transfer Capacitance (1)	f = 1 MHz		9.1	11.8		40	52	pF
R _G	Series Gate Resistance (1)			5	6.4		1.25	2.5	Ω
Q_g	Gate Charge Total (4.5 V) (1)			3.9	5		8.9	11.5	nC
Q_{gd}	Gate Charge – Gate-to-Drain	V _{DS} = 15 V,		0.9			2.5		nC
Q_{gs}	Gate Charge – Gate-to-Source	I _{DS} = 8 A		1.2			2		nC
$Q_{g(th)}$	Gate Charge at V _{th}			0.7			1.3		nC
Q _{OSS}	Output Charge	V _{DD} = 12 V, V _{GS} = 0 V		4.9			8.5		nC
t _{d(on)}	Turn On Delay Time			6.7			7.9		ns
t _r	Rise Time	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5$		19.3			16.3		ns
t _{d(off)}	Turn Off Delay Time	$I_{DS} = 8 \text{ A}, R_{G} = 2 \Omega$		10.6			16.8		ns
\mathfrak{t}_f	Fall Time			3			2.9		ns
DIODE CH	HARACTERISTICS								
V _{SD}	Diode Forward Voltage	I _{DS} = 8 A, V _{GS} = 0 V		0.85			0.79		V
Q _{rr}	Reverse Recovery Charge	V _{dd} = 15 V, I _F = 8 A,		8			16		nC
t _{rr}	Reverse Recovery Time	di/dt = 300 A/µs		13			17		ns

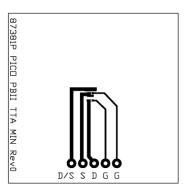
⁽¹⁾ Specified by design

⁽²⁾ Device mounted on FR4 material with 1 inch² (6.45 cm²) Cu.





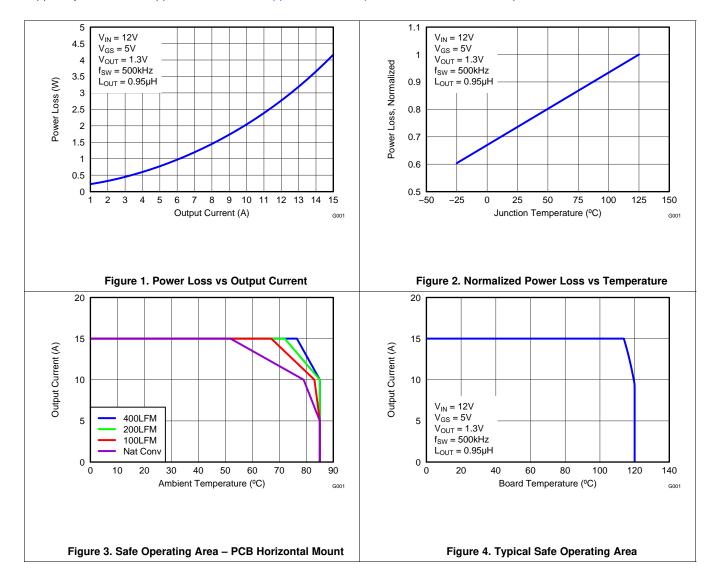
Max $R_{\theta JA} = 84^{\circ} C/W$ when mounted on 1 inch² (6.45 cm²) of 2 oz. (0.071 mm thick) Cu.



Max $R_{\theta JA} = 184^{\circ}C/W$ when mounted on minimum pad area of 2 oz. (0.071 mm thick) Cu.

5.6 Typical Power Block Characteristics

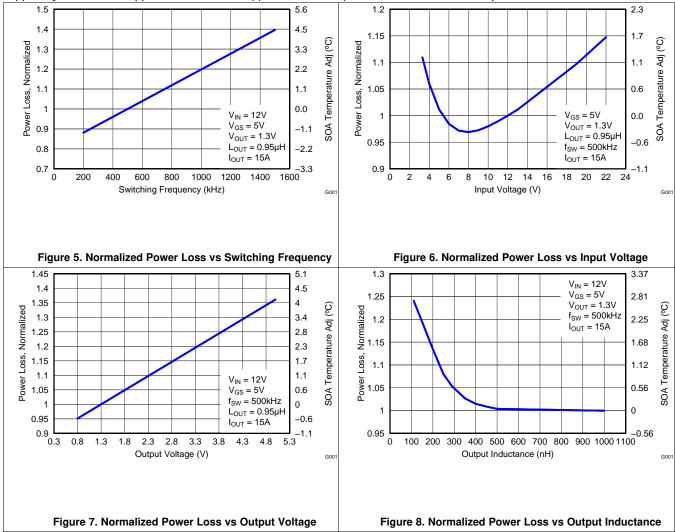
 $T_J = 125$ °C, unless stated otherwise. For Figure 3 and Figure 4, the Typical Power Block System Characteristic curves are based on measurements made on a PCB design with dimensions of 4 inches (W) \times 3.5 inches (L) \times 0.062 inch (H) and 6 copper layers of 1 oz. copper thickness. See *Application and Implementation* for detailed explanation.





Typical Power Block Characteristics (continued)

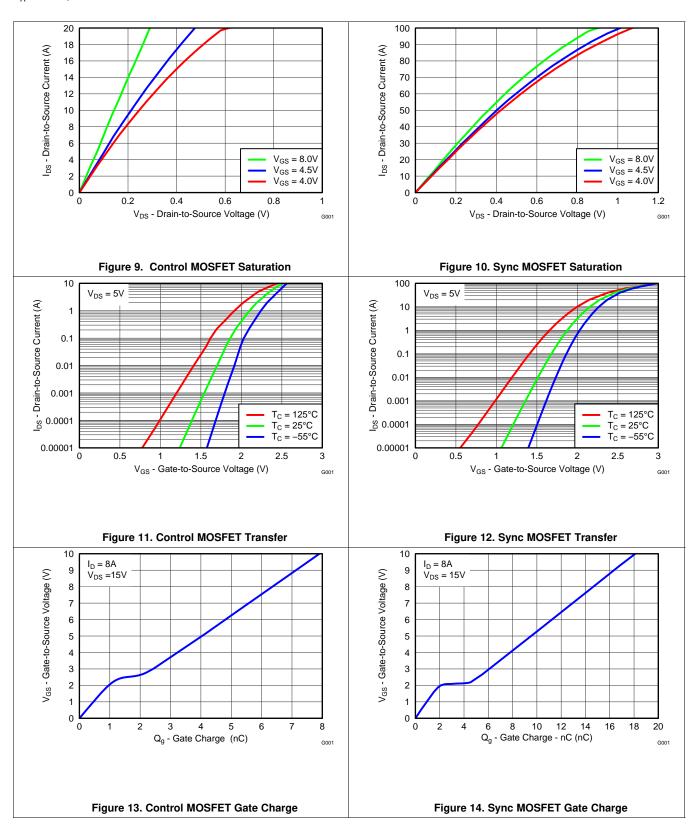
 $T_J = 125$ °C, unless stated otherwise. For Figure 3 and Figure 4, the Typical Power Block System Characteristic curves are based on measurements made on a PCB design with dimensions of 4 inches (W) × 3.5 inches (L) × 0.062 inch (H) and 6 copper layers of 1 oz. copper thickness. See *Application and Implementation* for detailed explanation.





5.7 Typical Power Block MOSFET Characteristics

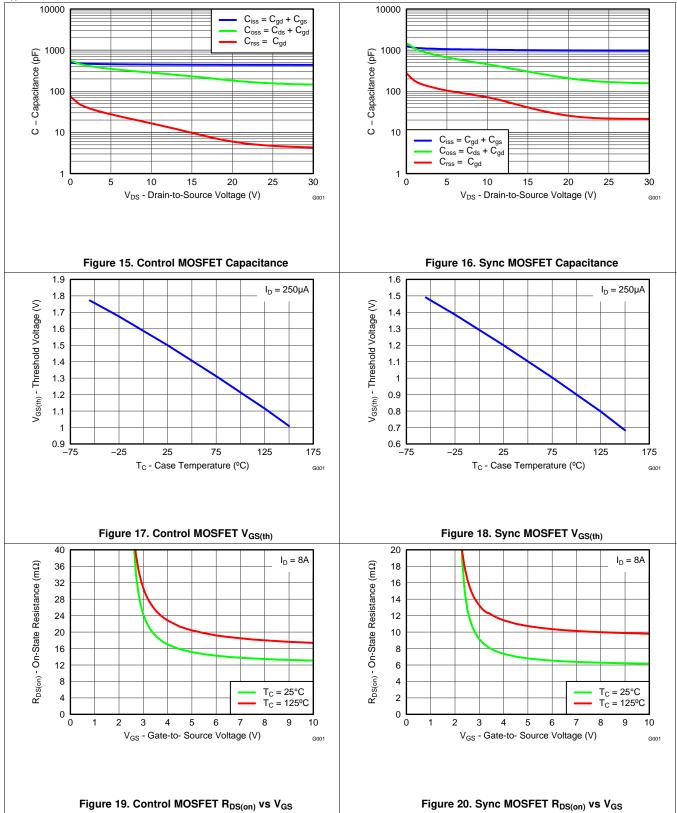
 $T_A = 25$ °C, unless stated otherwise.



TEXAS INSTRUMENTS

Typical Power Block MOSFET Characteristics (continued)

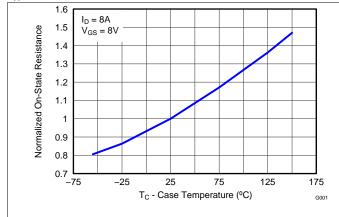
 $T_A = 25$ °C, unless stated otherwise.





Typical Power Block MOSFET Characteristics (continued)

 $T_A = 25$ °C, unless stated otherwise.



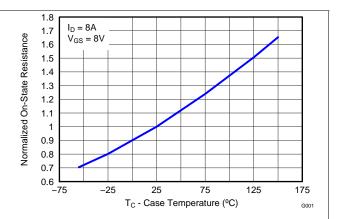


Figure 21. Control MOSFET Normalized R_{DS(on)}

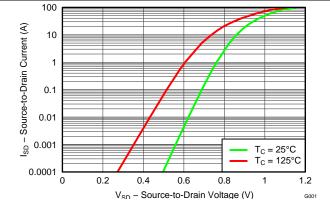


Figure 22. Sync MOSFET Normalized R_{DS(on)}

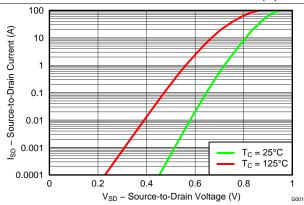


Figure 23. Control MOSFET Body Diode

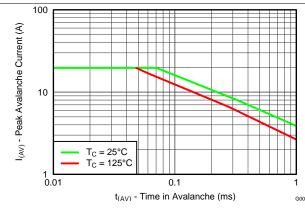


Figure 25. Control MOSFET Unclamped Inductive Switching

Figure 24. Sync MOSFET Body Diode

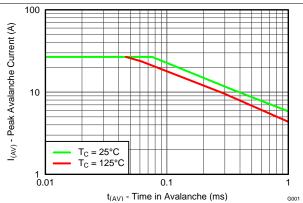


Figure 26. Sync MOSFET Unclamped Inductive Switching



6 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI 's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

6.1 Application Information

The CSD87381P NexFET power block is an optimized design for synchronous buck applications using 5 V gate drive. The control FET and sync FET silicon are parametrically tuned to yield the lowest power loss and highest system efficiency. As a result, a new rating method is needed, which is tailored towards a more systems-centric environment. System-level performance curves such as Power Loss, Safe Operating Area, and normalized graphs allow engineers to predict the product performance in the actual application.

6.1.1 Power Loss Curves

MOSFET-centric parameters such as $R_{DS(ON)}$ and Q_{gd} are needed to estimate the loss generated by the devices. In an effort to simplify the design process for engineers, TI has provided measured power loss performance curves. Figure 1 plots the power loss of the CSD87381P as a function of load current. This curve is measured by configuring and running the CSD87381P as it would be in the final application (see Figure 27). The measured power loss is the CSD87381P loss and consists of both input conversion loss and gate drive loss. Equation 1 is used to generate the power loss curve.

$$(V_{IN} \times I_{IN}) + (V_{DD} \times I_{DD}) - (V_{SW AVG} \times I_{OUT}) = Power Loss$$
 (1)

The power loss curve in Figure 1 is measured at the maximum recommended junction temperatures of 125°C under isothermal test conditions.

6.1.2 Safe Operating Curves (SOA)

The SOA curves in the CSD87381P data sheet provides guidance on the temperature boundaries within an operating system by incorporating the thermal resistance and system power loss. Figure 3 to Figure 4 outline the temperature and airflow conditions required for a given load current. The area under the curve dictates the safe operating area. All the curves are based on measurements made on a PCB design with dimensions of 4 inches $(W) \times 3.5$ inches $(L) \times 0.062$ inch (T) and 6 copper layers of 1 oz. copper thickness.

6.1.3 Normalized Curves

The normalized curves in the CSD87381P data sheet provide guidance on the power loss and SOA adjustments based on their application-specific needs. These curves show how the power loss and SOA boundaries adjust for a given set of systems conditions. The primary y-axis is the normalized change in power loss, and the secondary y-axis is the change is system temperature required in order to comply with the SOA curve. The change in power loss is a multiplier for the power loss curve, and the change in temperature is subtracted from the SOA curve.



Application Information (continued)

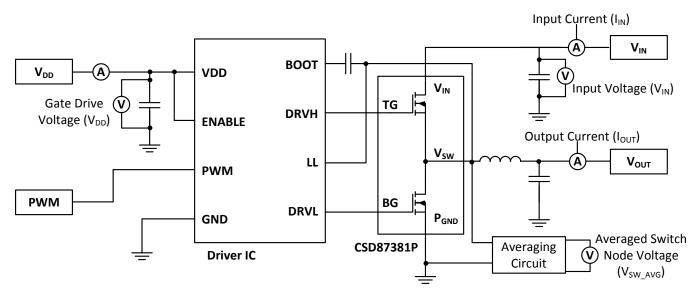


Figure 27. Typical Application



Application Information (continued)

6.1.4 Calculating Power Loss and SOA

The user can estimate product loss and SOA boundaries by arithmetic means (see *Design Example*). Though the power loss and SOA curves in this data sheet are taken for a specific set of test conditions, the following procedure outlines the steps the user should take to predict product performance for any set of system conditions.

6.1.4.1 Design Example

Operating Conditions:

- Output Current = 8 A
- Input Voltage = 4 V
- Output Voltage = 1 V
- Switching Frequency = 800 kHz
- Inductor = $0.2 \mu H$

6.1.4.2 Calculating Power Loss

- Power Loss at 8 A = 1.44 W (Figure 1)
- Normalized Power Loss for input voltage ≈ 1.06 (Figure 6)
- Normalized Power Loss for output voltage ≈ 0.97 (Figure 7)
- Normalized Power Loss for switching frequency ≈ 1.11 (Figure 5)
- Normalized Power Loss for output inductor ≈ 1.13 (Figure 8)
- Final calculated power loss = 1.44 W \times 1.06 \times 0.97 \times 1.11 \times 1.13 \approx 1.86 W

6.1.4.3 Calculating SOA Adjustments

- SOA adjustment for input voltage ≈ 0.7°C (Figure 6)
- SOA adjustment for output voltage ≈ -0.3°C (Figure 7)
- SOA adjustment for switching frequency ≈ 1.03°C (Figure 5)
- SOA adjustment for output inductor ≈ 1.5°C (Figure 8)
- Final calculated SOA adjustment = 0.7 + (-0.3) + 1.3 + 1.5 ≈ 2.2°C

In the previous design example, the estimated power loss of the CSD87381P would increase to 1.86 W. In addition, the maximum allowable board or ambient temperature, or both, would have to decrease by 2.2°C. Figure 28 graphically shows how the SOA curve would be adjusted accordingly.

- 1. Start by drawing a horizontal line from the application current to the SOA curve.
- 2. Draw a vertical line from the SOA curve intercept down to the board or ambient temperature.
- 3. Adjust the SOA board or ambient temperature by subtracting the temperature adjustment value.



Application Information (continued)

In the design example, the SOA temperature adjustment yields a reduction in allowable board or ambient temperature of 2.2°C. In the event the adjustment value is a negative number, subtracting the negative number would yield an increase in allowable board or ambient temperature.

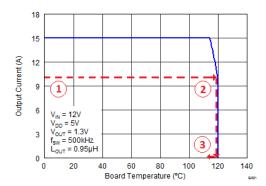


Figure 28. Power Block SOA

7 Layout

7.1 Layout Guidelines

7.1.1 Recommended PCB Design Overview

There are two key system-level parameters that can be addressed with a proper PCB design: electrical and thermal performance. Properly optimizing the PCB layout yields maximum performance in both areas. The following provides a brief description on how to address each parameter.

7.1.2 Electrical Performance

The CSD87381P has the ability to switch voltages at rates greater than 10 kV/μs. Take care with the PCB layout design and placement of the input capacitors, inductor, and output capacitors.

- The placement of the input capacitors relative to VIN and PGND pins of CSD87381P device should have the highest priority during the component placement routine. It is critical to minimize these node lengths. As such, ceramic input capacitors need to be placed as close as possible to the VIN and PGND pins (see Figure 29). The example in Figure 29 uses 1 x 10 nF 0402 25 V and 4 x 10 µF 1206 25 V ceramic capacitors (TDK part number C3216X5R1C106KT or equivalent). Notice there are ceramic capacitors on both sides of the board with an appropriate amount of vias interconnecting both layers. In terms of priority of placement next to the power stage, C21, C5, C8, C19, and C18 should follow in order.
- The switching node of the output inductor should be placed relatively close to the Power Block II CSD87381P VSW pins. Minimizing the VSW node length between these two components will reduce the PCB conduction losses and actually reduce the switching noise level. See Figure 29. (1)

7.1.3 Thermal Performance

The CSD87381P has the ability to utilize the PGND planes as the primary thermal path. As such, the use of thermal vias is an effective way to pull away heat from the device and into the system board. Concerns of solder voids and manufacturability problems can be addressed by the use of three basic tactics to minimize the amount of solder attach that wicks down the via barrel:

- Intentionally space out the vias from each other to avoid a cluster of holes in a given area.
- Use the smallest drill size allowed in your design. The example in Figure 29 uses vias with a 10 mil drill hole and a 16 mil capture pad.
- · Tent the opposite side of the via with solder-mask.

The number and drill size of the thermal vias should align with the end user's PCB design rules and manufacturing capabilities.

7.2 Layout Example

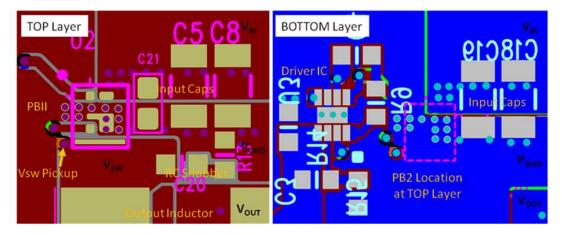


Figure 29. Recommended PCB Layout (Top Down View)

 Keong W. Kam, David Pommerenke, "EMI Analysis Methods for Synchronous Buck Converter EMI Root Cause Analysis", University of Missouri – Rolla



8 Device and Documentation Support

8.1 Trademarks

NexFET is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

8.2 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

8.3 Glossary

SLYZ022 — TI Glossary.

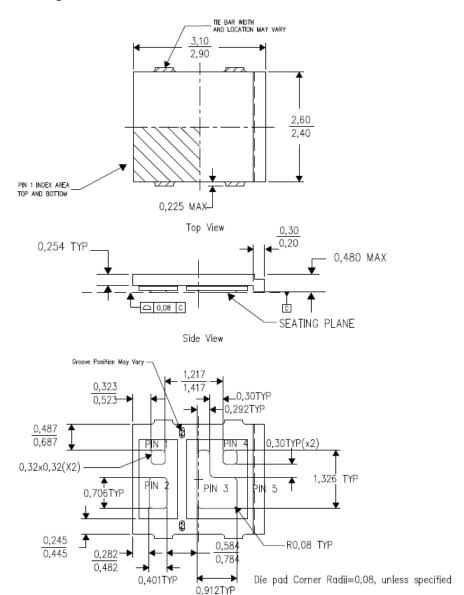
This glossary lists and explains terms, acronyms, and definitions.



9 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

9.1 CSD87381P Package Dimensions



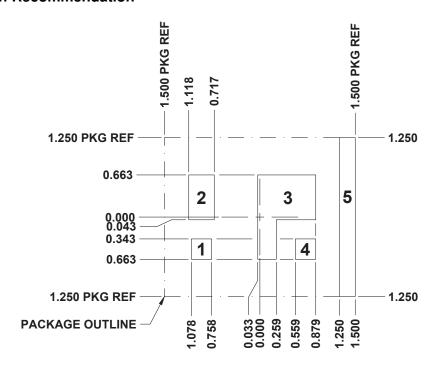
Pin Configuration

Bottom View

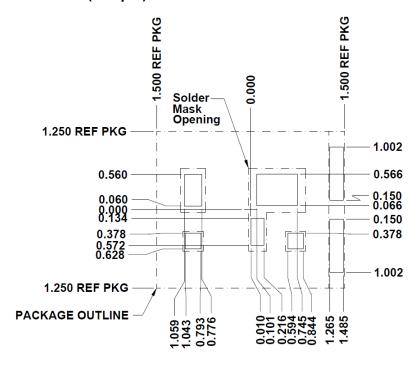
Position	Designation
Pin 1	TG
Pin 2	V_{IN}
Pin 3	P_{GND}
Pin 4	BG
Pin 5	V _{SW}



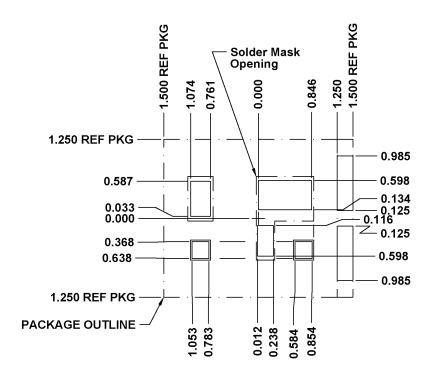
9.2 Land Pattern Recommendation



9.3 Stencil Recommendation (100 µm)



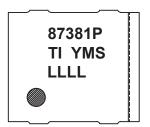
9.4 Stencil Recommendation (125 µm)



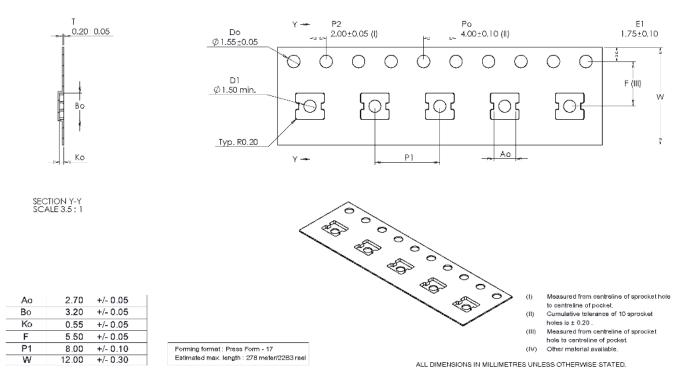
For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.



9.5 Pin Drawing



9.6 CSD87381P Embossed Carrier Tape Dimensions



(1) Pin 1 is oriented in the top-left quadrant of the tape enclosure (closest to the carrier tape sprocket holes).



PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CSD87381P	ACTIVE	PTAB	MPC	5	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 150	87381P	Samples
CSD87381PT	ACTIVE	PTAB	MPC	5	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 150	87381P	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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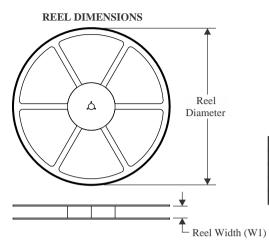


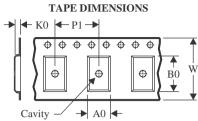
10-Dec-2020

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

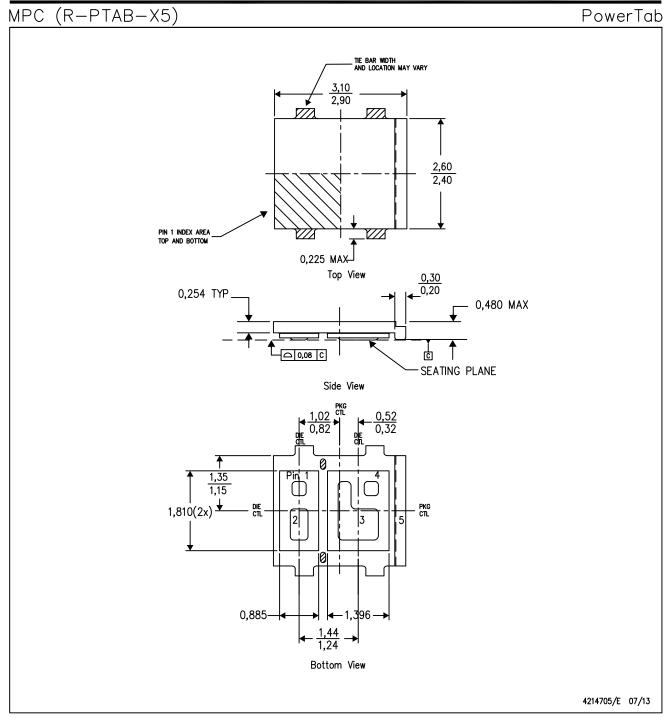
Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CSD87381P	PTAB	MPC	5	2500	330.0	12.4	2.7	3.2	0.55	8.0	12.0	Q1
CSD87381PT	PTAB	MPC	5	250	180.0	12.4	2.7	3.2	0.55	8.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CSD87381P	PTAB	MPC	5	2500	346.0	346.0	33.0
CSD87381PT	PTAB	MPC	5	250	182.0	182.0	20.0



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.



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